## **Listing of the Claims:**

The following listing of claims will replace any/all prior versions, and listings, of claims in the application:

1. (Original) A cleaning solution for photoresist patterns comprising:

H<sub>2</sub>O as a solvent; and

a compound represented by following Formula 1 as a surfactant:

Formula 1

$$R = \begin{cases} O & O \\ A & O \\ O & O \end{cases}$$

$$O & O \\ O & O \\ O & O \end{cases}$$

$$O & O \\ Y & O \\ Y & O \\ O & O \\ O$$

wherein

R is  $C_2$ - $C_{20}$  alkyl or  $C_6$ - $C_{25}$  alkyl aryl;

x, y and z individually are an integer ranging from 0 to 10;

a is 2 or 3; and

b is an integer ranging from 2 to 50.

- 2. (Original) The cleaning solution according to claim 1, wherein the b is an integer ranging from 6 to 11.
- 3. (Original) The cleaning solution according to claim 1, further comprising an alcohol.
- 4. (Original) The cleaning solution according to claim 1, wherein the compound of Formula 1 is present in an amount ranging from 0.001 to 2 wt% based on the total weight of said solution.
- 5. (Original) The cleaning solution according to claim 3 wherein the alcohol is present in an amount ranging from 0 to 20 wt% based on the total weight of said solution.

**6**. (Original) The cleaning solution according to claim **1**, wherein the compound of Formula 1 is represented by Formula 2 or Formula 3:

Formula 2

Formula 3

wherein

R is  $C_2$ - $C_{20}$  alkyl or  $C_6$ - $C_{25}$  alkyl aryl;

- x, y and z individually are an integer ranging from 0 to 10; and n is an integer ranging from 1 to 49.
- 7. (Original) The cleaning solution according claim 6, wherein the compound of Formula 2 is present in an amount ranging from 0.001 to 2 wt% based on the total weight of said solution, and the alcohol is present in an amount ranging from 0 to 20 wt% based on the total weight of said solution.
- **8**. (Original) The cleaning solution according to claim **6**, wherein the compound of Formula 3 is present in an amount ranging from 0.001 to 2 wt% based on the total weight of said solution, and the alcohol is present in an amount ranging from 0 to 10 wt% based on the total weight of said solution.

- 9. (Original) The cleaning solution according to claim 7, wherein the compound of Formula 2 is present in an amount ranging from 0.01 to 1 wt% based on the total weight of said solution, and the alcohol is present in an amount ranging from 0.01 to 10 wt% based on the total weight of said solution.
- 10. (Original) The cleaning solution according to claim 8, wherein the compound of Formula 3 is present in an amount ranging from 0.001 to 1 wt% based on the total weight of said solution, and the alcohol is present in an amount ranging from 0.001 to 5 wt% based on the total weight of said solution.
- **11.** (Original) The cleaning solution according to claim **6**, wherein R is selected from the group consisting of octyl, octyl phenyl, nonyl, nonyl phenyl, decyl, decyl phenyl, undecyl, undecyl phenyl, dodoecyl and dodecyl phenyl, and n is an integer ranging from 5 to 10.
- 12. (Original) The cleaning solution according to claim 3, wherein the alcohol is selected from the group consisting of  $C_1$ - $C_{10}$  alkyl alcohol,  $C_1$ - $C_{10}$  alkoxyalkyl alcohol, and mixtures thereof.
- 13. (Original) The cleaning solution according to claim 12, wherein the  $C_1$ - $C_{10}$  alkyl alcohol is selected from the group consisting of methanol, ethanol, propanol, isopropanol, n-butanol, sec-butanol, t-butanol, 1-pentanol, 2-pentanol, 3-pentanol, 2,2-dimethyl-1-propanol and mixtures thereof.
- 14. (Original) The cleaning solution according to claim 12, wherein the  $C_1$ - $C_{10}$  alkoxyalkyl alcohol is selected from the group consisting of 2-methoxyethanol, 2-(2-methoxyethoxy)ethanol, 1-methoxy-2-propanol, 3-methoxy-1,2-propandiol and mixtures thereof.
- 15. (Original) The cleaning solution according to claim 1, wherein the solution is selected from the group consisting of

mixture comprising the compound of Formula 2 as a surfactant wherein R is nonyl; x, y and z are 1, respectively; and n is 7, methanol as an alcohol and water as a solvent;

mixture comprising the compound of Formula 2 as a surfactant wherein R is octyl; x, y and z are 1, respectively; and n is 7, methanol as an alcohol and water as a solvent;

mixture comprising the compound of Formula 2 as a surfactant wherein R is dodecyl; x, y and z are 0, respectively; and n is 7, isopropanol as an alcohol and water as a solvent;

mixture comprising the compound of Formula 2 as a surfactant wherein R is octyl phenyl; x, y and z are 1, respectively; and n is 3, isopropanol as an alcohol and water as a solvent;

mixture comprising the compound of Formula 3 as a surfactant wherein R is nonyl; x, y and z are 1, respectively; and n is 7, methanol as an alcohol and water as a solvent;

mixture comprising the compound of Formula 3 as a surfactant wherein R is octyl; x, y and z are 1, respectively; and n is 7, methanol as an alcohol and water as a solvent;

mixture comprising the compound of Formula 3 as a surfactant wherein R is dodecyl; x, y and z are 0, respectively; and n is 7, isopropanol as an alcohol and water as a solvent; and

mixture comprising the compound of Formula 3 as a surfactant wherein R is octyl phenyl; x, y and z are 1, respectively; and n is 3, isopropanol as an alcohol and water as a solvent.

- **16.** (Original) The cleaning solution according to claim **15**, wherein the surfactant of Formula 2 is present in an amount ranging from 0.001 to 2 wt% based on the total weight of said mixture, and the alcohol is present in an amount ranging from 0 to 20 wt% based on the total weight of said mixture.
- 17. (Original) The cleaning solution according to claim 15, wherein the surfactant of Formula 3 is present in an amount ranging from 0.001 to 2 wt% based on the total weight of said mixture, and the alcohol is present in an amount ranging from 0 to 10 wt% based on the total weight of said mixture.
- 18. (Original) The cleaning solution according to claim 16, wherein the surfactant of Formula 2 is present in an amount ranging from 0.01 to 1 wt% based on the total weight of said mixture, and the alcohol is present in an amount ranging from 0.01 to 10 wt% based on

the total weight of said mixture.

- 19. (Original) The cleaning solution according to claim 17, wherein the surfactant of Formula 3 is present in an amount ranging from 0.001 to 1 wt% based on the total weight of said mixture, and the alcohol is present in an amount ranging from 0.001 to 5 wt% based on the total weight of said mixture.
  - 20. (Withdrawn) A method for forming a photoresist pattern, comprising:
  - (a) preparing a semiconductor substrate on which an underlying layer is formed;
    - (b) coating a photoresist on the underlying layer to form a photoresist film;
    - (c) exposing the photoresist film to light;
    - (d) developing the exposed photoresist film; and
    - (e) cleaning the resulting structure using the cleaning solution of claim 1.
- **21**. (Withdrawn) The method according to claim **20**, further comprising soft baking step before part (c) or post baking step after part (c).
- **22**. (Withdrawn) The method according to claim **20**, wherein the source of the light is selected from the group consisting of KrF (248 nm), ArF (193 nm), VUV (157 nm), EUV (13 nm), E-beam, X-ray and ion-beam.
- 23. (Withdrawn) A semiconductor device manufactured by the method of claim20.